

Contents

Part I Macroscopic Techniques

1 Contact Angle and Wetting Properties	3
Yuehua Yuan and T. Randall Lee	
1.1 Introduction	3
1.2 Theoretical Background	4
1.2.1 Surface Tension and Contact Angle—Young’s Equation	4
1.2.2 Contact Angle Hysteresis	5
1.3 Experimental Setup and Method	7
1.3.1 Direct Measurement by Telescope-Goniometer	7
1.3.2 Captive Bubble Method	10
1.3.3 Tilting Plate Method	10
1.3.4 Wilhelmy Balance Method	11
1.3.5 Capillary Rise at a Vertical Plate	13
1.3.6 Individual Fiber	13
1.3.7 Capillary Tube	14
1.3.8 Capillary Penetration Method for Powders and Granules	15
1.3.9 Capillary Bridge Method	16
1.4 Applications of the Technique	17
1.5 Recent Developments of the Technique	19
1.5.1 Drop Shape Analysis	19
1.5.2 Axisymmetric Drop Shape Analysis (ADSA)	20
1.5.3 Contact Angle Measurement of Ultrasmall Droplets	22
1.6 Summary	28
References	29
2 Adsorption Calorimetry on Well-Defined Surfaces	35
Ole Lytken, Hans-Jörg Drescher, Rickmer Kose, and J. Michael Gottfried	
2.1 Introduction	35
2.2 Theory Background	36
2.2.1 Approaches for the Measurement of Adsorption Energies	36

2.2.2	Thermodynamics	37
2.3	Experimental Setup and Method	40
2.3.1	History	40
2.3.2	Single-Crystal Adsorption Calorimeter by D.A. King	41
2.3.3	Single-Crystal Adsorption Calorimeter by C.T. Campbell	43
2.3.4	Electrochemical Single-Crystal Adsorption Calorimeter by R. Schuster	45
2.4	Applications of the Technique	46
2.4.1	Surface Phase Transitions—CO Adsorption on Pt	46
2.4.2	Reaction Intermediates—Cyclohexene Adsorption on Pt(111)	48
2.4.3	Metal Adsorption on Polymers—Calcium on Poly(3-Hexylthiophene)	49
2.4.4	Particle-Size Dependent Adsorption Energies—CO on Pd	51
2.5	Future Developments of the Technique	52
	References	53

Part II Optical Techniques

3	Methods of IR Spectroscopy for Surfaces and Thin Films	59
	David Allara and Josh Stapleton	
3.1	Introduction and Scope	59
3.2	Basic Principles of Plane Wave Interactions with Planar Film Stacks and Associated Constraints on Sampling Modes and Surface Characterization Attributes at IR Wavelengths	62
3.2.1	Basic Theory for Low to Moderate Intensity Beams (First Order Scattering Regime)	62
3.2.2	The Interaction of Parallel Plane EM Waves with Planar Film Stacks—Transmission, Reflection and Evanescent Wave Sampling	65
3.2.3	General Characterization Capabilities and Features in the IR Wavelength Region	68
3.3	Quantitative Aspects—Spectral Simulations	71
3.3.1	Spectroscopic Intensities in Terms of the Absorption Properties of Materials	71
3.3.2	Electromagnetic Fields in Planar Thin Film Structures	72
3.4	Instrumentation and Operating Conditions	80
3.4.1	Overview	80
3.4.2	Typical Components	81
3.4.3	Major Sampling Modes and Typical Associated Sampling Conditions and Requirements	84
3.4.4	Typical Signal/Noise Characteristics	85
3.5	Application Examples	87
3.5.1	Transmission	88
3.5.2	Reflection	89
3.5.3	External Reflection	89

3.5.4	Examples of Spectral Simulations and Quantitative Analyses of Spectra	92
3.6	Future Directions	96
	References	97
4	A Surface Scientist’s View on Spectroscopic Ellipsometry	99
	Maurizio Canepa	
4.1	Introduction	99
4.2	Basics on Principles, Methods and Systems	100
4.2.1	The Fundamental Relation of Ellipsometry: Ψ and Δ	101
4.2.2	The Prototypical System: Isotropic Thin Film on a Substrate	102
4.2.3	Ultrathin Films and Monolayers	107
4.3	Instrumentation and Experimental Configurations	109
4.3.1	Basic SE Instruments	109
4.3.2	In-situ Real-Time Measurements	112
4.3.3	Null Ellipsometry and Imaging	114
4.4	A Survey of Applications of Spectroscopic Ellipsometry to Ultrathin Films and Other Nanosystems	115
4.4.1	Ultrathin Films: Inorganic Dielectrics (Mainly Oxides)	115
4.4.2	Ultrathin Films: Organic and Biologic Films	117
4.4.3	Nanostructures	122
4.4.4	Graphene	126
4.5	Concluding Remarks	127
	References	127
5	Nonlinear Vibrational Spectroscopy	137
	Lee J. Richter	
5.1	Introduction	137
5.2	Fundamentals	138
5.2.1	Nonlinear Polarization	138
5.2.2	The Susceptibility	140
5.3	Experimental Considerations	143
5.3.1	Experimental Configuration	143
5.3.2	Laser Sources	145
5.4	Data Treatment	150
5.4.1	Normalization	150
5.4.2	Spectral Analysis	151
5.5	Examples	153
5.6	Future	157
	References	158
	Part III X-Ray Techniques	
6	Grazing Incidence X-Ray Diffraction	165
	Osami Sakata and Masashi Nakamura	
6.1	Introduction	165
6.2	Theory and Background	167

6.2.1	Real-Space Geometry and Reciprocal-Space Scans Used for Surface X-Ray Diffraction	167
6.2.2	Structure Factor	170
6.2.3	Outline of Data Collection for Structure Determination	172
6.2.4	From Measured Intensities to Structure Factors	172
6.2.5	Structural Analysis	173
6.2.6	Effect of Number of Measured Structure Factors	176
6.3	Experimental Setup and Method	176
6.3.1	Beamline Components	176
6.3.2	X-Ray Source and Optics	177
6.3.3	Examples of Diffractometers	178
6.4	Applications	181
6.4.1	Interface Atomic Structures: Electric Double Layer at the Solid Electrode	181
6.4.2	Quick Evaluation of Thin Film Structure: Identification of Crystal Symmetry of an Epitaxial Thin Film	183
6.5	Conclusions	189
	References	189
7	X-Ray Reflectivity	191
	A. Gibaud, M.S. Chebil, and T. Beuvier	
7.1	Introduction	191
7.2	The Basic Principles of X-Ray Reflectivity	193
7.2.1	The Index of Refraction	193
7.2.2	The Critical Angle of Reflection	193
7.2.3	Reflected Intensity from Ideally Flat Surface	194
7.2.4	Importance of Surface Roughness	195
7.2.5	X-Ray Reflection by Planar Multilayers with Flat and Rough Interfaces	196
7.2.6	The Refraction Matrix for X-Ray Radiation	198
7.2.7	Reflection from a Flat Homogeneous Material	199
7.2.8	A Single Layer on a Substrate	199
7.3	From Dynamical to Kinematical Theory	201
7.3.1	The Master Equation in Kinematical Theory	201
7.3.2	The Patterson Function	203
7.4	Experimental Setup and Method	205
7.4.1	Footprint Effect	205
7.4.2	Instrumental Resolution	205
7.5	Recent Applications of the Technique	206
7.5.1	Contrast Matching	207
7.5.2	X-Ray Porosimetry	207
7.5.3	XRR for Samples Under Pressurized Fluids	212
7.6	Conclusion	214
	References	215

8	Resonant Photoelectron Diffraction	217
	Alberto Verdini, Peter Krüger, and Luca Floreano	
8.1	Introduction	217
8.2	Theoretical Outline	220
8.2.1	Resonant Photoemission	220
8.2.2	Angular Dependence of Resonant Photoemission	222
8.3	Angular PED Analysis	224
8.3.1	The Isotropic Component	224
8.3.2	The Anisotropy χ -Function	227
8.3.3	Simulation of PED and RESPED Angular Patterns	227
8.3.4	Surface Refraction	229
8.4	Application of Resonant PED	229
8.4.1	Resonant Valence Band PED	229
8.4.2	Resonant Auger ED	239
8.5	Conclusions	243
	References	244
9	Surface Structure Analysis with X-Ray Standing Waves	249
	Jörg Zegenhagen	
9.1	Introduction	249
9.2	X-Ray Standing Wave Technique for Surface Analysis: Milestones	251
9.3	Basic Principle of the XSW Technique	253
9.4	X-Ray Absorption, Photoelectron Emission and Subsequent Decay Channels	255
9.5	Structural Analysis: XSW as Fourier Technique	258
9.6	Structural Analysis: Simple Interpretation of XSW Results	262
9.7	Experimental	263
9.8	XSW Fluorescence Analysis: Electrodeposited Versus UHV Deposited Cu on GaAs(001)	266
9.9	XSW Photoelectron Spectroscopy: Chemically Resolved Surface Structure of Sn on Ge(111)	270
9.10	Conclusion and Outlook	272
	References	273
10	Advanced Applications of NEXAFS Spectroscopy for Functionalized Surfaces	277
	Alexei Nefedov and Christof Wöll	
10.1	Introduction	277
10.2	Theory Background	281
10.3	Experimental Method and Setup	286
10.4	Applications of NEXAFS Spectroscopy	291
10.4.1	Structural Rearrangements at Organic/Metal Interfaces	291
10.4.2	Internal Twist Structure in Aromatic Self-assembled Monolayers	295
10.4.3	Coverage Dependent Orientation of Terephthalic Acid Molecules on TiO ₂ (110)	299

10.5 Conclusions	301
References	301
Part IV Neutral Particle Techniques	
11 Neutron Reflectivity	307
Frédéric Ott	
11.1 Introduction	307
11.2 Principle of Specular Reflectivity	309
11.3 Experimental Setup and Method	312
11.3.1 Monochromatic Reflectometers	312
11.3.2 Time of Flight Reflectometers	312
11.4 Applications of Specular Neutron Reflectivity	313
11.4.1 Polymer Systems	313
11.4.2 Solid-Liquid Interfaces	314
11.4.3 Biological Model Systems	316
11.4.4 Oxide Layers	317
11.4.5 Interface Magnetism	319
11.4.6 Probing μm Scale In-Plane Structures: Off-Specular Scattering	321
11.4.7 Probing nm Scale In-Plane Structures: Grazing Incidence Small Angle Scattering	325
11.5 Future Developments of the Technique	328
References	329
12 Probing Surfaces with Thermal He Atoms: Scattering and Microscopy with a Soft Touch	333
Bodil Holst and Gianangelo Bracco	
12.1 Introduction	333
12.2 The Basic Principles of HAS	340
12.2.1 Kinematics of the Scattering	341
12.3 The Experimental Setup in HAS	349
12.4 An Application Example: Structural Properties of the α -Quartz(0001) Surface	352
12.4.1 Surface Preparation	352
12.4.2 Surface Structure	353
12.5 Outlook: Neutral Helium Microscopy (NEMI)	354
12.5.1 Focusing Elements	357
12.5.2 Detection	358
References	358
13 The Helium Spin-Echo Method	367
Andrew Jardine	
13.1 Introduction	367
13.1.1 Quasi-elastic HAS: A Unique Probe of Surface Dynamics	369
13.1.2 The Historical Development of HeSE	370
13.2 Theory Background	370

13.2.1 Principles of Helium Scattering	370
13.2.2 The Spin-Echo Technique	372
13.2.3 The ISF as a Correlation Function	374
13.2.4 Semi-classical Formalism & Correlation Interpretation	375
13.2.5 Wavelength Transfer Matrix & Tilted Projection Formalism	375
13.3 Experimental Setup and Method	376
13.3.1 General Characteristics	377
13.3.2 Spin-Manipulation	378
13.3.3 Using HeSE to Study Adsorbate Dynamics	379
13.3.4 HeSE Signatures for Simple Forms of Motion	380
13.3.5 Signatures for More Complex Forms of Motion	381
13.3.6 Complimentary Tools: MC and MD Numerical Simulations	383
13.4 Applications of the Technique	384
13.4.1 Self-diffusion and Adsorbate-Substrate Potentials	384
13.4.2 Diffusion on Non-Bravais Lattices	386
13.4.3 Measurement of Inter-adsorbate Interaction Potentials	388
13.4.4 Larger Molecules	390
13.4.5 Quantum Contributions & Tunnelling	390
13.4.6 Other Applications	392
13.5 Future Developments of the Technique	393
13.5.1 Instrumentation & Analysis	393
13.5.2 Future Applications	393
References	394
14 Diffraction of H₂ from Metal Surfaces	397
Daniel Farías, Marina Minniti, and Rodolfo Miranda	
14.1 Introduction	397
14.2 Theory Background	399
14.3 Experimental Setup and Method	401
14.3.1 General Requirements	401
14.3.2 ‘Rotary Detector’ Setup	404
14.3.3 ‘Fixed-Angle’ Setup	406
14.4 Applications of the Technique	407
14.4.1 General Trends	407
14.4.2 H ₂ /Pt(111)	410
14.4.3 H ₂ /Ru(0001)	412
14.4.4 D ₂ /NiAl(110)	414
14.5 Future Developments	417
References	418
Part V Charged Particle Techniques	
15 Low Energy Ion Scattering and Recoiling Spectroscopy in Surface Science	423
Vladimir A. Esaulov	
15.1 Introduction	423

15.2 Basic Principles	425
15.2.1 Energy Losses in Elastic Collisions	425
15.2.2 Electronic Stopping	427
15.2.3 Scattering Cross Section and Interaction Potentials	428
15.2.4 Shadowing, Blocking and ICISS	429
15.2.5 Special Features in Grazing Scattering	432
15.2.6 Quantification and Neutralization Effects	433
15.3 Experimental Setups and Methods	438
15.3.1 Ion Beam Lines	438
15.3.2 Energy Loss Measurements Using Electrostatic Analyzers	439
15.3.3 Time of Flight Systems	444
15.4 Applications of Ion Scattering	447
15.4.1 Study of Growth of Metal Clusters on TiO ₂	448
15.4.2 Study of Metal Deposition on an Organic Layer	450
15.4.3 Study of O(2 × 1)–Ag(110) Missing-Row Reconstruction by ICISS	451
15.4.4 Study of Growth of Organic Layer on a Au(111) Surface by TOF SARS	452
15.4.5 Chlorine Adsorption on Ag and Electron Transfer Effects. A TOF and LEIS Study	454
15.5 Concluding Remarks	455
References	456
16 Helium Ion Microscopy	461
Diederik J. Maas and Raoul van Gastel	
16.1 Introduction	461
16.1.1 Brief History of Ultra Microscopy	463
16.2 Theory and Background	465
16.2.1 Helium Ion Interaction with the Target	465
16.2.2 Secondary Electron Generation	467
16.2.3 Backscattered He Imaging	470
16.2.4 Backscattered He Spectroscopy	471
16.2.5 Other Modes of Operation	473
16.2.6 Sample Damage and Nanofabrication	473
16.3 Experimental Setup	474
16.3.1 Ion Source	474
16.3.2 Probe Size	475
16.3.3 Ion Optical Column	476
16.3.4 Image Resolution	477
16.3.5 Vacuum Performance	478
16.4 Applications of the Technique	480
16.4.1 Imaging of Non-conductive Samples	480
16.4.2 Critical Dimension Metrology on EUV Resist with SEM and HIM	480
16.4.3 Imaging of Self-assembled Monolayers	482

16.4.4 TEM Lamella Preparation by DW Helium Ion Beam Milling	485
16.4.5 Helium Ion Beam Induced Processing (He-IBIP)	488
16.5 Summary	491
References	492
17 High Resolution Electron Energy Loss Spectroscopy (HREELS): A Sensitive and Versatile Surface Tool	499
Luca Vattuone, Letizia Savio, and Mario Rocca	
17.1 Introduction	499
17.2 Inelastic Scattering Mechanisms	503
17.2.1 Dipole Scattering	503
17.2.2 Impact Scattering	506
17.2.3 Resonance Scattering	509
17.3 Experimental Setups	511
17.4 Selected Experimental Results	514
17.4.1 HREELS for the Study of Adsorbates and Surface Chemistry	514
17.4.2 HREELS for the Measurement of Dispersion Curves of Collective Surface Excitations: Surface Plasmons and Surface Phonons	517
17.4.3 HREELS as a Tool to Evaluate the Density of Carriers	520
17.4.4 HREELS as a Tool to Investigate Interband Transitions	522
17.4.5 HREELS and Superconductivity	522
17.4.6 SP-EELS Detection of Spin Waves	523
17.4.7 HREELS for the Investigation of Liquid Surfaces	524
17.5 The Future of HREELS	525
References	526
18 Low-Energy Electron Microscopy	531
Juan de la Figuera and Kevin F. McCarty	
18.1 Introduction	531
18.2 Background	534
18.2.1 Magnetic Contrast	537
18.2.2 Resolution	538
18.3 Experimental Setup and Methods	538
18.4 Applications	544
18.4.1 Observation of Clean Surfaces	544
18.4.2 Surface Dynamics: From Adatoms to Phase Transitions	545
18.4.3 Thin Film Growth: From Self-assembly to Film Dewetting	547
18.4.4 Determining Surface Crystallography and Electronic Structure	551
18.4.5 Advantages and Limitations vs Other Surface Imaging Techniques	555
18.5 Future Developments	556
References	556

Part VI Scanning Probe Techniques	
19 Scanning Tunneling Microscopy	565
Ada Della Pia and Giovanni Costantini	
19.1 Introduction	565
19.2 Theory of Tunneling	566
19.3 Experimental Setup	570
19.3.1 Scanner and Coarse Positioner	571
19.3.2 Electronics and Control System	573
19.3.3 Tip	574
19.3.4 Vibration Isolation	576
19.3.5 Setups for Different Environments and Temperatures	577
19.4 STM Imaging	578
19.5 Scanning Tunneling Spectroscopy	580
19.5.1 $I(V)$ Spectroscopy	581
19.5.2 Constant-Current Tunneling Spectra	584
19.5.3 CITS	585
19.5.4 $s(V)$ Spectroscopy	586
19.5.5 $I(s)$ Spectroscopy	587
19.5.6 Orbital Mediated Tunneling Spectroscopy	588
19.5.7 Inelastic Electron Tunneling Spectroscopy	590
19.6 Tip-Induced Modification	593
References	595
20 Surface Characterization Using Atomic Force Microscopy (AFM) in Liquid Environments	599
Venetia D. Lyles, Wilson K. Serem, Jing-Jiang Yu, and Jayne C. Garno	
20.1 Introduction	599
20.2 Theory Background	600
20.2.1 History of AFM	600
20.2.2 Early Benchmarks for Studies Using Liquid AFM	601
20.3 Experimental Setup and Method	601
20.3.1 Basic Operating Principle of AFM	601
20.3.2 Approaches for Liquid Imaging	602
20.4 Applications of AFM in Liquids	603
20.4.1 High Resolution AFM Imaging in Liquids	604
20.4.2 Measurement of Surface Forces in Liquid Media	606
20.4.3 <i>In situ</i> Studies of Chemical Reactions with Liquid AFM	608
20.4.4 Electrochemistry Studies with AFM in Liquids	609
20.4.5 Nanofabrication with AFM in Liquid Media	611
20.4.6 AFM Studies of Biological Samples in Liquids	613
20.5 Future Developments of Liquid AFM	617
References	618
21 Atomic Force Microscopy for Surface Imaging and Characterization of Supported Nanostructures	621
Franciszek Krok, Bartosz Such, Jacek J. Kolodziej, and Marek Szymonski	

21.1 Introduction	621
21.2 Theory Background	623
21.2.1 Interaction Forces in AFM	623
21.2.2 Dynamics of Cantilever in NC-AFM	625
21.2.3 Reverse Problem in NC-AFM	626
21.3 Experimental Setup and Methods	627
21.3.1 Contact Atomic Force Microscopy	627
21.3.2 Non-contact Atomic Force Microscopy	629
21.3.3 Kelvin Probe Force Microscopy	631
21.4 Applications of the Technique	632
21.4.1 NC-AFM of Semiconductor Surfaces	632
21.4.2 NC-AFM of Nanostructured Insulator Surfaces	637
21.4.3 Au Islands Supported on InSb	640
21.4.4 NC-AFM of Supported Molecules	640
21.4.5 KPFM of Supported Nanostructures	641
21.4.6 Friction Force Microscopy Measurements at Atomic-Scale	644
21.5 Future Development of the Technique	647
References	650
Index	655